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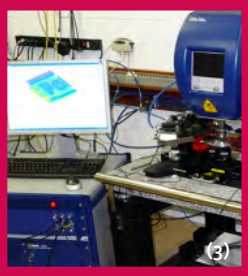
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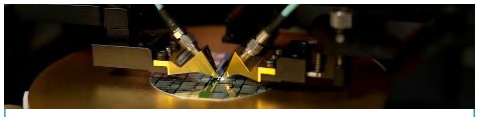
WELCOME : Wallonia Electronics and Communications Measurements

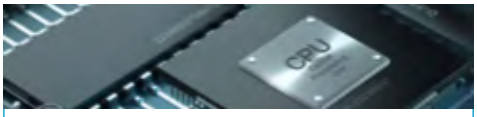
WHAT WE OFFER : services and expertise

- Service & expertise in electro-magnetic characterization of materials, devices, sensors, circuits, systems
- Access to characterization infrastructure / Equipment renting accomplished by training (if necessary)
- Measurement campaign realized by UCLouvain staff / PCB assembly and prototyping
- Technical advice and consultancy / Training for R&D engineers from industry
- Collaborative research



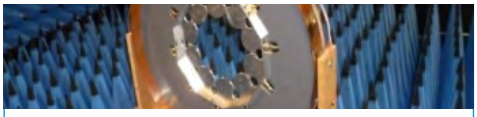
Materials, passive and active electron devices and sensors

- Multi-port and multi-parametric (electro-mechanical, optical stimuli, gases, etc.) characterization
- From DC to 125 GHz,
- Temperature range from 4 to 600 K
- Small-signal and nonlinear regimes



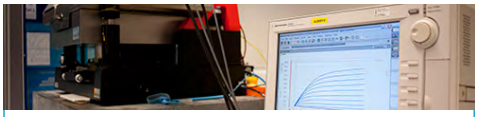
Analog/digital circuits and systems-in-package

- µcontrollers, smart cards, RFIDs, FPGAs, etc.
- Using ultra low current probes, mixed-signal and real-time oscilloscopes, analog waveform and digital pattern generators, etc.



Radar and wireless telecommunications

- Broadband signal generation and signal analysis capabilities
- Using variety of Vector Network and Spectrum Analysers
- In a free-space, waveguide and coax, multi-path or anechoic environment



Remarkable equipment

- Probe stations: MPI : 300mm (20-300°C); Lakeshore: 51mm (4-500K)
- ALFNA noise analyzer (1/f, RTN)
- Large-band VNA: 900 Hz-125 GHz /2 ports; PNA-X: 26.5 GHz/4-ports
- Anechoic chamber: 0.4 - 40 GHz and 60-90 GHz
- PolyTec vibrometer

Collaborative research

- Support to the research projects submission and realization (FNRS, RW, EC, Ecsel, Innoviris, etc.)
- Support to spin-offs, SMEs, knowledge transfer
- Links with other academic labs via SiNANO Institute joint platforms: www.sinano.eu

CONTACT

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www.uclouvain.be/welcome

(1) IV, CV, RF and noise characterization up to 300°C – (2) IV & RF Cryogenic (4K) on Wafer Prober - (3) MEMS/NEMS/Sensors Tests – (4) Anechoic Chamber – (5) RF materials tests

welcome
UCLouvain

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Soutenu par
Le Brabant wallon
Avec le soutien de la Wallonie